

Statistical Geophysics

Chapter 3

Inferential Statistics 2

Inferential Statistics 2

Introduction to hypothesis testing

Background

- So far, we have considered problems of estimation.
- We will now study what are generally called tests of hypotheses.
- These tests yield a binary decision that a particular hypothesis about a phenomenon generating the data may be true or not.
- There are two types of tests: parametric tests and nonparametric (or distribution-free) tests.

Sampling distribution

- The sampling distribution for a statistic (including the test statistic for a hypothesis test) is the probability distribution describing batch-to-batch variations of that statistic.
- The value of a statistic computed from a particular batch of data will in general be different from that for the same statistic computed using a different batch of data of the same kind.
- Example: Average January temperature is obtained by averaging daily temperatures during that month at a particular location for a given year. The statistic is different from year to year.

Elements of any hypothesis test

- Identify a test statistic that is appropriate to the data and question at hand.
- ② Define a null hypothesis, H_0 , which defines a reference against which to judge the observed test statistic.
- **3** Define an alternative hypothesis, H_1 (or H_A).
- Obtain the null distribution, which is the sampling distribution for the test statistic, if H₀ is true.
- Compare the observed test statistic to the null distribution. If the test statistic falls in a sufficiently improbable region of the null distribution, H₀ is rejected as too implausible to have been true given the observed evidence.

Test level

- The sufficiently improbably region of the null distribution is defined by the rejection level (or test level) of the test.
- H₀ is rejected if the probability of the observed test statistic, and all other results at least as unfavourable to H₀, is less than or equal to the test level.
- The test level is chosen in advance of the computations.
- Commonly the 5% level is chosen, although tests conducted at the 10% level or the 1% level are not unusual.

p value

- The p value is the probability that the observed value of the test statistic, together with all other possible values of the test statistic that are at least as unfavourable to H₀, will occur.
- Thus, H₀ is rejected if the p value is less than or equal to the test level and is not rejected otherwise.
- The p value also communicates the confidence with which a null hypothesis has or has not been rejected.

Error types and power of a test

	H_0 is true	H_0 is false
H_0 is rejected	Type I error	No error
H_0 is not rejected	No error	Type II error

We define

$$lpha = P(type\ I\ error) = P(reject\ H_0|H_0\ true)$$

 $eta = P(type\ II\ error) = P(not\ reject\ H_0|H_0\ false)\ .$

The quantity $1 - \beta$ is known as the power of a test against a specific alternative.

Error types and power of a test

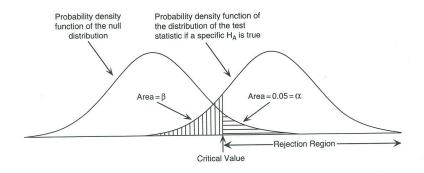


Figure: Illustration of the relationship of the probability of a Type I error (horizontal hatching) and the probability of a Type II error (vertical hatching) for a test conducted at the 5% level.

One-sided versus two-sided tests

- A statistical test can be either one-sided or two-sided.
- A one-sided test is appropriate
 - ...if there is a prior reason to expect that violations of H_0 will lead to values of the test statistic on a particular side of the null distribution.
 - ...when only values on one tail or the other of the null distribution are unfavorable to H₀, because the way the test statistic has been constructed.
- Two-sided tests are appropriate when either very large or very small values of the test statistic are unfavourable to the null distribution.

Confidence intervals: inverting hypothesis tests

- There is a duality between a one-sample hypothesis test and the computed confidence interval (CI) around the observed statistic.
- The 100 \times (1 $-\alpha$)% CI around an observed statistic
 - will not contain the null hypothesis value of the test if the test is significant at the α level,
 - and will contain the null value if the test is not significant at the α level.

Example: Exact binomial test

- Advertisements for a tourist resort claim that, on average, six days out of seven are cloudless during winter (6/7 = 0.857).
- Assume that we could arrange to take observations on 25 independent occasions.
- If cloudless skies are observed on 15 of those 25 days, is this observation consistent with, or does it justify questioning, the claim?
- This problem fits neatly into the parametric setting of the binomial distribution.

Example: Exact binomial test

- The test statistic of X = 15 out of n = 25 days has been dictated by the form of the problem.
- Test problem: H_0 : $\pi \ge 0.857$ vs. H_1 : $\pi < 0.857$.
- For this test, the null distribution is binomial, with parameters n=25 and $\pi=0.857$.
- The p value of this exact binomial test is

$$P(X \le 15) = \sum_{x=0}^{15} \begin{pmatrix} 25 \\ x \end{pmatrix} 0.857^{x} (1 - 0.857)^{25-x} = 0.0015 .$$

Example: Exact binomial test

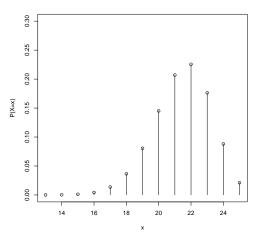


Figure: Exact binomial null distribution $\mathcal{B}(n=25,\pi=0.857)$.

Approximate binomial test

Approximation of the binomial distribution:

• Let $X = \sum_{i=1}^{n} X_i \sim \mathcal{B}(n, \pi)$. It follows from the Central Limit Theorem that for sufficiently large n:

$$X \stackrel{a}{\sim} \mathcal{N}(n\pi, n\pi(1-\pi))$$

and

$$Z = \frac{X - n\pi}{\sqrt{n\pi(1-\pi)}} \stackrel{a}{\sim} \mathcal{N}(0,1)$$
.

Approximate binomial test

Summary

- Suppose the following test problems for the parameter π of the $\mathcal{B}(n,\pi)$ distribution:
 - (a) $H_0: \pi = \pi_0 \text{ vs. } H_1: \pi \neq \pi_0$
 - **(b)** $H_0: \pi \geq \pi_0 \text{ vs. } H_1: \pi < \pi_0$
 - (c) $H_0: \pi \leq \pi_0 \text{ vs. } H_1: \pi > \pi_0$.
- Based on the observed test statistic

$$z = \frac{x - n\pi_0}{\sqrt{n\pi_0(1 - \pi_0)}} = \frac{\hat{\pi} - \pi_0}{\sqrt{\frac{\pi_0(1 - \pi_0)}{n}}}$$

and given α , H_0 is rejected if

- (a) $|z| > z_{1-\alpha/2}$
- **(b)** $z < -z_{1-\alpha}$
- (c) $z > z_{1-\alpha}$.

Example: Approximate binomial test

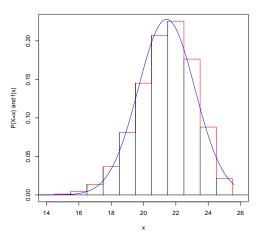


Figure: Relationship of the binomial null distribution (histogram bars), and its Gaussian approximation (smooth curve).

Continuity correction

Approximation of the binomial with continuity correction:

• Let $X \sim \mathcal{B}(n, \pi)$. For sufficiently large n:

$$P(X \le x) \approx \Phi\left(\frac{x + 0.5 - n\pi}{\sqrt{n\pi(1 - \pi)}}\right)$$

$$P(X = x) \approx \Phi\left(\frac{x + 0.5 - n\pi}{\sqrt{n\pi(1 - \pi)}}\right) - \Phi\left(\frac{x - 0.5 - n\pi}{\sqrt{n\pi(1 - \pi)}}\right).$$

Inferential Statistics 2

Some commonly encountered parametric tests

t test for the mean

- We want to compare a hypothetical mean, μ_0 , with the true unknown mean μ .
- If the number of data values making up the sample mean is large enough for its sampling distribution to be essentially Gaussian, then the test statistic

$$T = \frac{\bar{X} - \mu_0}{S} \sqrt{n} ,$$

where $S = \sqrt{\sum_{i=1}^{n} (X_i - \bar{X})^2/(n-1)}$, follows a t distribution with n-1 degrees of freedom (d.f.).

• The statistic T resembles the standard Gaussian variable $Z = \frac{\bar{X} - \mu_0}{\sigma} \sqrt{n}$, except that a sample estimate of the variance of the sample mean has been substituted in the denominator.

t test for the mean

Summary

- Consider the test problems:
 - (a) $H_0: \mu = \mu_0 \text{ vs. } H_1: \mu \neq \mu_0$
 - **(b)** $H_0: \mu \ge \mu_0$ vs. $H_1: \mu < \mu_0$
 - (c) $H_0: \mu \leq \mu_0 \text{ vs. } H_1: \mu > \mu_0$.
- Based on the observed test statistic

$$t = \frac{\bar{x} - \mu_0}{s} \sqrt{n}$$

and given α , H_0 is rejected if

- (a) $|t| > t_{1-\alpha/2}(n-1)$
- **(b)** $t < t_{\alpha}(n-1) = -t_{1-\alpha}(n-1)$
- (c) $t > t_{1-\alpha}(n-1)$.
- For $n \ge 30$: Approximate quantiles of the t distribution of n-1 d.f. by quantiles of the $\mathcal{N}(0,1)$ distribution.

Comparison of two proportions

- Suppose the data are categorized into two groups.
- Let π_1 (π_2) be the probability of success in group 1 (group 2).
- Test problem H_0 : $\pi_1 = \pi_2$ vs. H_1 : $\pi_1 \neq \pi_2$.
- Sample is presented as a two-by-two contingency table:

	Group 1	Group 2	\sum
Success	10	15	25
Failure	20	15	35
\sum	30	30	60

Proportions of success:

Group 1:
$$\frac{10}{30} = 33\% = \hat{\pi}_1$$
, Group 2: $\frac{15}{30} = 50\% = \hat{\pi}_2$.

Test statistic

The test statistic is

$$\chi^2 = \sum_{i=1}^4 \frac{(o_i - e_i)^2}{e_i} ,$$

where i = 1, ..., 4 are the four cells in the middle of the contingency table.

• The o_i are the observed counts and the e_i are what is expected if $\pi_1 = \pi_2$.

Computing e_i

- If H_0 : $\pi_1 = \pi_2$ is true, we could estimate the common probability π by $\hat{\pi} = 25/60 = 0.4167$.
- In the upper left corner we would expect to see $0.4167 \times 30 = 12.501$ successes in group 1, and so 30 12.501 = 17.499 failures in the lower left.
- In the upper right corner we would expect to see $0.4167 \times 30 = 12.501$ successes in group 2, and so 30 12.501 = 17.499 failures in the lower right.

Decision

• The value of the observed test statistic χ^2 is

$$\chi^{2} = \frac{(10 - 12.501)^{2}}{12.501} + \frac{(20 - 17.499)^{2}}{17.499} + \frac{(15 - 12.501)^{2}}{12.501} + \frac{(15 - 17.499)^{2}}{17.499} = 1.7142.$$

- The sampling distribution of this test statistic is the χ^2 distribution with 1 degrees of freedom (d.f.).
- Reject H_0 if $\chi^2 > \chi^2_{1-\alpha}(1)$.
- $\chi^2 = 1.7142 < \chi^2_{0.95}(1) = 3.8415$. The observed difference is statistically not significant at the 5% level (p value = 0.1905).

Inferential Statistics 2

Test for differences of mean under independence

Example: comparison of two fertilizers

- Response: crop yield.
- Two independent samples (each with sample size n = 6).
- Crop yield using
 - fertilizer X: 22, 21, 18, 16, 22, 17.
 - fertilizer Y: 20, 22, 17, 13, 17, 18.
- μ_X (μ_Y) denotes the mean crop yield using fertilizer X (Y).
- Test problem: H_0 : $\mu_X = \mu_Y$ vs. H_1 : $\mu_X \neq \mu_Y$.

Two-sample t test

- $X_k \overset{i.i.d.}{\sim} \mathcal{N}(\mu_X, \sigma_X^2)$ (k = 1, ..., n) and $Y_l \overset{i.i.d.}{\sim} \mathcal{N}(\mu_Y, \sigma_Y^2)$ (l = 1, ..., m).
- Assumption: $\sigma_X = \sigma_Y$ (unknown).
- Test problem: $H_0: \mu_X \mu_Y = \delta_0$ vs. $H_1: \mu_X \mu_Y \neq \delta_0$.
- Observed test statistic:

$$t = \frac{\bar{x} - \bar{y} - \delta_0}{\sqrt{\left(\frac{1}{n} + \frac{1}{m}\right) \left\{\frac{(n-1)s_x^2 + (m-1)s_y^2}{n+m-2}\right\}}} \ .$$

• Reject H_0 , if $|t| > t_{1-\frac{\alpha}{2}}(n+m-2)$.

Example:

The sample means are

$$\bar{x} = \frac{1}{6}(22 + 21 + 18 + 16 + 22 + 17) = 19.33$$

$$\bar{y} = \frac{1}{6}(20 + 22 + 17 + 13 + 17 + 18) = 17.83$$

- The observed difference is $\bar{x} \bar{y} = 1.5$.
- An estimate for the pooled sample variance is 8.2167.
- The value of the observed test statistic is $t = \frac{1.5}{\sqrt{\frac{1}{3} \times 8.2167}} = 0.9064$.
- Decision: $t = 0.9064 < t_{0.975}(10) = 2.2814$: H_0 is not rejected (p value = 0.386).

Inferential Statistics 2

Test for differences of mean for paired samples

Paired t test

- An important from of non-independence occurs when the data values are paired.
- The two-sample t test for paired data analyzes the differences $D_i = X_i Y_i$ (i = 1, ..., n) between corresponding members of the $n_1 = n_2 = n$ pairs.
- The test statistic is

$$T = \frac{\bar{D} - \mu_D}{S_D} \sqrt{n} ,$$

where
$$\bar{D} = \frac{1}{n} \sum_{i=1}^{n} D_i$$
, $\mu_D = \mu_X - \mu_Y$ and $S_D = \sqrt{\frac{1}{n-1} \sum_{i=1}^{n} (D_i - \bar{D})^2}$.

The test problem is transformed to the one-sample setting.